S	eard	ch	No	te:	S



10/662,831

Examiner Cong-Lac Huynh

Applicant(s)/Patent	under
Reexamination	

HASKELL ET AL.
Art Unit

2178

	SEAR	CHED	
Class	Subclass	Date	Examiner
715	500.1	11/2/2006	CLH
	716	11/2/2006	CLH
	727	11/2/2006	CLH

INT	INTERFERENCE SEARCHED		
Class	Subclass	Date	Examiner
	I		
		·	
		,	

SE (INCLUDING	EARCH NOTES G SEARCH STR	ATEGY)	
		DATE	EXMR
East	11/	/2/2006	
Google	11/	/2/2006	CLH
IEEE	12/	18/2006	CLH
	-		